22.38 PROBABILITY AND ITS APPLICATIONS TO RELIABILITY, QUALITY CONTROL AND RISK ASSESSMENT

Fall 2005

PROBLEM SET #9

Due December 6, 2005

- 1. For the component testing program discussed in the class of November 10, which change of 10% is the value of t_t , t_R , f_R and Q_o , respectively, would be most valuable in reducing the value of <Q> (use the numerical parameter values employed for in-class illustrative calculations as the base case)?
- 2. Consider a two-component parallel system consisting of identical components. Each component has two failure modes, mode 1 and 2, having frequencies, λ₁ and λ₂, respectively. Mode 1 failures can be repaired at frequency, μ, and mode 2 failures cannot be repaired. Formulate the possible system states and corresponding state transition diagram, and state rate of change matrix. What are the absorbing states of the system? Why?
- 3. Consider a component subject to loads that are normally distributed (with mean, $\mu_L = 8$, and standard deviation, $\sigma_L = 2$). The component's capability is also normally distributed (with mean, $\mu_c = 15$, and standard deviation, $\sigma_c = 5$). What is the reliability of the component?
- 4. Consider a system consisting of three parallel identical components where success of a single component is sufficient for system success. Use the β-factor method to quantify the contribution of common cause failures to overall system unreliability. At what value of β is the reliability of the three-component parallel system equal to that of a two-component system, for which only independent failures are considered? Let the independent failure probability of single component be equal to 10⁻³.
- 5. The reliability of a component is governed by the exponential distribution, $f_T(t) = \lambda e^{-\lambda t}$, where t is the time of component failure. The prior distribution of λ is uniform over the interval $\lambda = [10^{-3}, 10^{-2}]$ hr⁻¹. The new evidence consists of component failures at times of 300, 400 and 800 hours, respectively. What is the posterior distribution of λ ?